

# Infrared Spectroscopic Study of Acetonitrile on SnO<sub>2</sub>-Based Thick Film and its Characteristics as a Gas Sensor

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The SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Pd and SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film sensors were fabricated by screen printing and dipping methods, and their sensing characteristics to CH<sub>3</sub>CN gas were investigated. The oxidation products of CH<sub>3</sub>CN on the thick film were analyzed by FT-IR using a heatable gas cell. For the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Pd thick film, metallic Pd played a great role as a co-catalyst for the oxidation of CH<sub>3</sub>CN. The IR results showed that the products formed by oxidation of CH<sub>3</sub>CN at 300°C on the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub> thick film without SiO<sub>2</sub> were mainly CO<sub>2</sub>, H<sub>2</sub>O, and NH<sub>3</sub>, while on the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film products such as CO<sub>2</sub>, H<sub>2</sub>O, N<sub>2</sub>O, HNO<sub>3</sub>, and HNO<sub>2</sub> were observed. The thick film devices containing SiO<sub>2</sub> showed high selectivity and negative sensitivity to CH<sub>3</sub>CN due to the presence of nitrogen compounds produced by oxidation of CH<sub>3</sub>CN. The optimum amount of Nb<sub>2</sub>O<sub>5</sub> and operating temperature were 1.0 wt% and 300°C, respectively. © 2000 Academic Press

## INTRODUCTION

Several commercial gas sensors make use of SnO<sub>2</sub> sensing elements. Gas sensors detecting a trace amount of the gases have applied to processes in the chemical, pharmaceutical, and fermentation industries to control the amount of the harmful wastes discharged from the plants, the explosion of the combustible gases and incomplete combustion, exhaust gases from automobiles, and testing in the clinics. The sensors show many advantages over optical or electrochemical sensors. The main advantages are their low cost, low consumption of electrical power, and high sensitivity.

The phenomenon of electrical conductivity changes induced in semiconducting materials by adsorption of gases on the solid surface is increasingly being used as a means of flammable and toxic gas detection. The working mechanism of thick film and sintered gas sensors is based on the buildup of Schottky barriers between adjacent grains caused by the ionosorbed oxygen (1).

Semiconductor gas sensors using SnO<sub>2</sub> and ZnO have been studied extensively since they were proposed by

Seiyama *et al.* (2). Successively, several research laboratories worked with the aim of developing new devices. The recent research on flammable gas sensors has concentrated on SnO<sub>2</sub> in the form of thick film and sintered ceramics (3–5).

However, sensors should be improved due to a lack of stability and a poor selectivity. The addition of small amounts of additives is known to provide better sensitivity and selectivity (6, 7). An improvement of the selectivity of sensors based on SnO<sub>2</sub> is generally obtained by adding some specific catalysts such as Pd or Pt for heavy combustible gases (8–10), CeO<sub>2</sub> for hydrogen (11), and ThO<sub>2</sub> for CO (12).

In this work, we have developed a SnO<sub>2</sub>-based sensor for the detection of acetonitrile gas, which is known to be a poisonous chemical at low levels in air. The sensing characteristics of a SnO<sub>2</sub>-based sensor to acetonitrile were studied by FT-IR analyses of gaseous species produced by oxidation of CH<sub>3</sub>CN on the sensor surface.

## EXPERIMENTAL

Al<sub>2</sub>O<sub>3</sub> (10.0 wt%) and Nb<sub>2</sub>O<sub>5</sub> (0.2–2.0 wt%) [or PdCl<sub>2</sub> (0–5.0 wt%)] were mechanically mixed with the base material, SnO<sub>2</sub>, followed by calcination in air at 600°C for 1 h. Al<sub>2</sub>O<sub>3</sub>, Nb<sub>2</sub>O<sub>5</sub>, SnO<sub>2</sub>, and PdCl<sub>2</sub> were obtained from Aldrich, Milwaukee, WI, where the purity of the samples was 99.9%. Al<sub>2</sub>O<sub>3</sub> was used to improve the stability of the fabricated sensor and to give a strong cohesion between the thick film and alumina substrate. The calcined sample was ground and then mixed with water to prepare a paste. The paste was screen-printed onto an alumina substrate and then dipped into tetraethylorthosilicate solution followed by sintering in air at 700°C for 1 h. Figure 1 shows the fabrication process of the thick film sensor. The sensor sensitivity was measured in a stainless steel box equipped with a heater, as described in a preceding publication (13).

The sensitivity is defined as  $R_g/R_0$ , where  $R_0$  and  $R_g$  are the electric resistances in fresh air and in the test gas, respectively. The products formed by the oxidation reaction of

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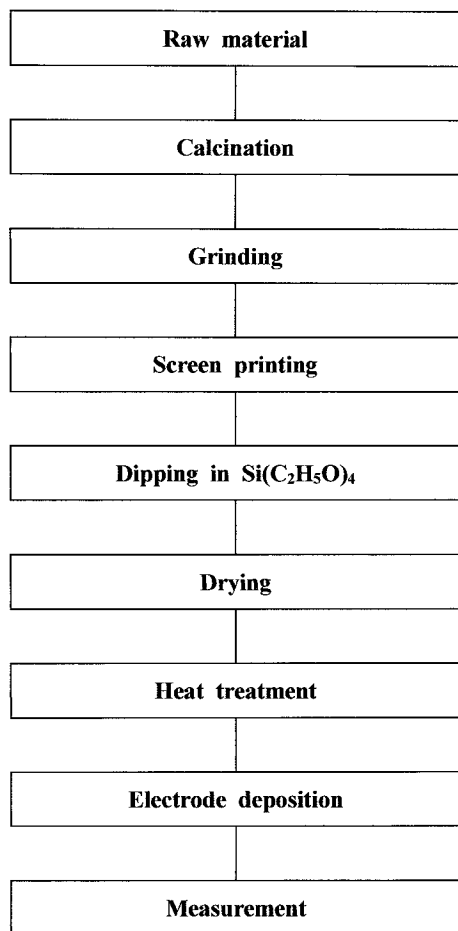


FIG. 1. Fabrication flow chart of a thick film sensor.

CH<sub>3</sub>CN on the sensor surface were analyzed by a Mattson Model GL 6030E FT-IR spectrometer using a heatable IR gas cell. FT-IR absorption spectra were measured over the range of 4000–400 cm<sup>-1</sup>.

X-ray photoelectron spectra were obtained with a VG Scientific model ESCALAB MK-11 spectrometer. Al *K*α and Mg *K*α were used as the excitation source, usually at 12 kV, 20 mA. The analysis chamber was at 10<sup>-9</sup> Torr or better, and the spectra of the sample, as fine powder, were analyzed. Binding energies were referenced to the C<sub>1s</sub> level of the carbon at 284.6 eV.

X-ray diffraction patterns of samples were obtained by means of a JEOL model JDX-8030 diffractometer, employing Cu *K*α (Ni-filtered) radiation. The specific surface area was determined by applying the BET method to the adsorption of N<sub>2</sub> at -196°C.

## RESULTS AND DISCUSSION

The optimum base material was selected based on the decomposition temperature of CH<sub>3</sub>CN on the surface of

TABLE 1  
Decomposition Temperature of CH<sub>3</sub>CN on Metal Oxides and Their Specific Surface Area

Metal oxide	Type	Decomposition temperature (°C)	Surface area (m <sup>2</sup> /g)
SnO <sub>2</sub>	n	130	5.0
WO <sub>3</sub>	n	150	4.4
CoO	p	200–220	4.5
TiO <sub>2</sub>	n	230	6.1
Fe <sub>2</sub> O <sub>3</sub>	n	250	3.0
ZnO	n	>300	4.8

various metal oxides and on the FT-IR analyses of the decomposed products. The decomposition temperature of CH<sub>3</sub>CN is defined as the temperature at which the decomposed products are observed in the IR spectra after the reaction for 0.5 h. The decomposition reaction was carried out in a heatable gas IR cell under the condition of 20 Torr CH<sub>3</sub>CN and 500 Torr air, where 16–20 Torr CH<sub>3</sub>CN was the most appropriate to observe the IR spectra in a gas cell. The decomposition temperature of CH<sub>3</sub>CN on metal oxides and their surface areas are listed in Table 1. On the surface of SnO<sub>2</sub>, CH<sub>3</sub>CN began to decompose at 130°C and many

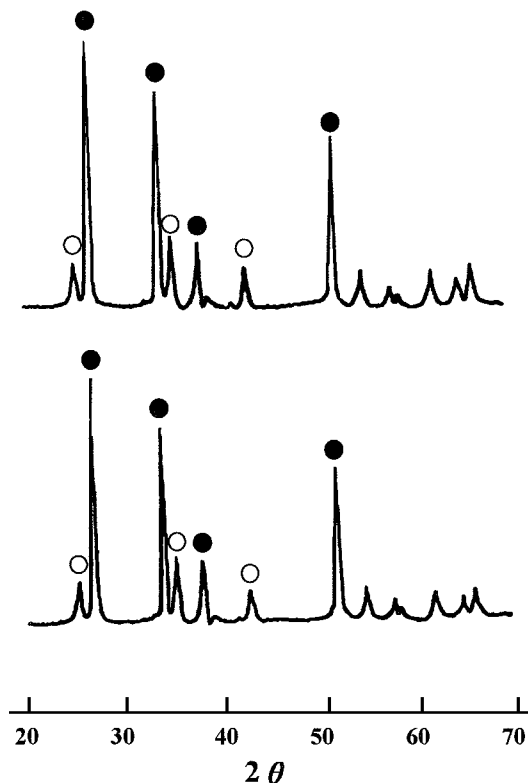
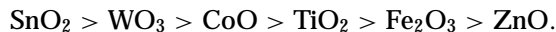


FIG. 2. X-ray diffraction patterns of SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub> and SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> calcined at 700°C for 1 h: ●, tetragonal phase of SnO<sub>2</sub>; ○, α-Al<sub>2</sub>O<sub>3</sub> phase.

products were produced at 300°C. The products from the decomposition reaction were H<sub>2</sub>O, NH<sub>3</sub>, CO<sub>2</sub>, and N<sub>2</sub>O. The easiness of decomposition on the surfaces of metal oxides falls in the following sequence:



The crystalline structures of SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub> and SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/N<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> sintered in air at 700°C for 1 h were examined. As shown in Fig. 2, for both samples only the tetragonal phase of SnO<sub>2</sub> and α-Al<sub>2</sub>O<sub>3</sub> phase were observed. The crystalline phases of Nb<sub>2</sub>O<sub>5</sub> and SiO<sub>2</sub> did not appear, indicating that they are amorphous or the crystallites formed are less than 4 nm in size, that is, beyond the detection capability of the XRD technique (14).

Figure 3 shows the IR spectra of CH<sub>3</sub>CN (16 Torr) and the oxidation products of CH<sub>3</sub>CN on SnO<sub>2</sub> and CoO thick films under the condition of 16 Torr CH<sub>3</sub>CN and 16 Torr

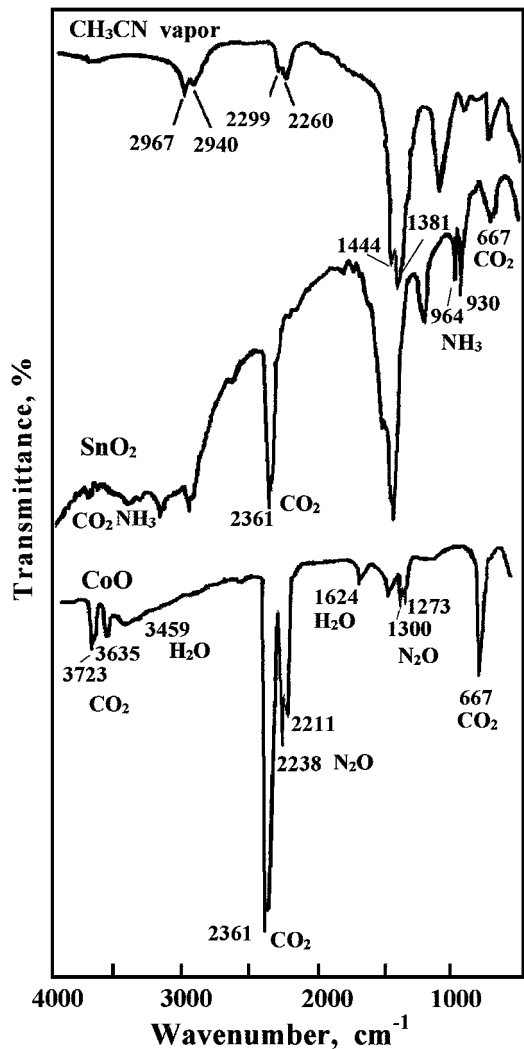


FIG. 3. Infrared spectra of CH<sub>3</sub>CN and the oxidation reaction products of CH<sub>3</sub>CN on SnO<sub>2</sub> and CoO thick films.

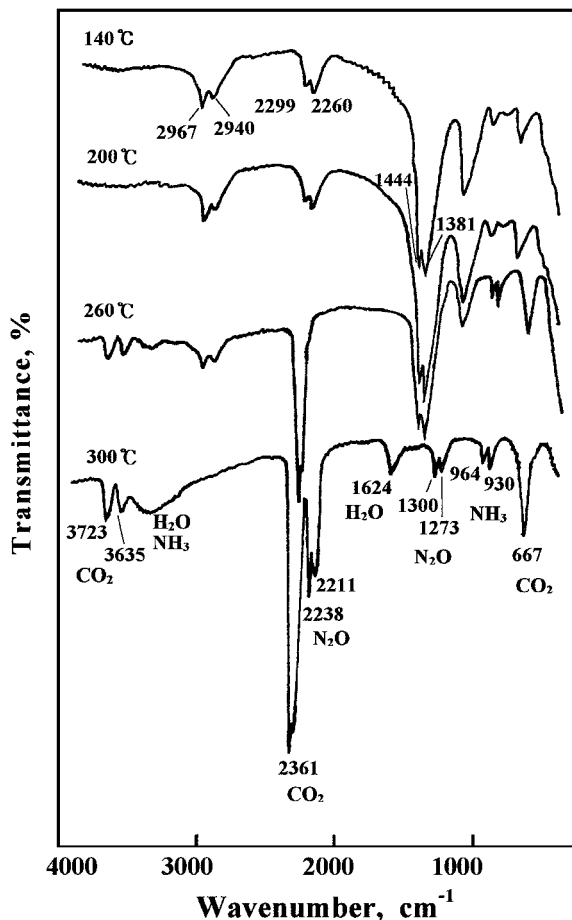
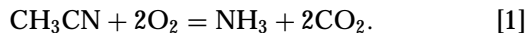


FIG. 4. Infrared spectra after an oxidation reaction of CH<sub>3</sub>CN on SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Pd (0.2 wt%) at various temperatures.

air at 300°C for 0.5 h. For pure CH<sub>3</sub>CN, the bands at 2967 and 2940 cm<sup>-1</sup> are assigned to the CH<sub>3</sub> stretching vibration mode, while those at 1444 and 1381 cm<sup>-1</sup> are ascribed to the CH<sub>3</sub> deformation (15). The bands at 2299 and 2260 cm<sup>-1</sup> are assigned to the CN stretching vibration. However, on the SnO<sub>2</sub>, the bands due to NH<sub>3</sub> and CO<sub>2</sub> in addition to CH<sub>3</sub>CN were observed as shown in Fig. 3. The bands at 3414, 1624, 964, and 930 cm<sup>-1</sup> are ascribed to the NH<sub>3</sub>, while those at 3723, 3635, 2361, and 667 cm<sup>-1</sup> are due to the CO<sub>2</sub> (16). Oxidation of CH<sub>3</sub>CN on SnO<sub>2</sub> seems to proceed by the following reaction:



On CoO, the bands due to CO<sub>2</sub> were observed similarly to the case of SnO<sub>2</sub>, but the bands due to NH<sub>3</sub> did not appear. Instead of NH<sub>3</sub> bands, those due to N<sub>2</sub>O and H<sub>2</sub>O were observed. The bands at 2238 and 2211 cm<sup>-1</sup> (doublet) and 1300 and 1273 cm<sup>-1</sup> (doublet) are ascribed to the N<sub>2</sub>O (16), while those at 3459 and 1624 cm<sup>-1</sup> are due to the H<sub>2</sub>O. N<sub>2</sub>O and H<sub>2</sub>O seem to form by the oxidation of NH<sub>3</sub> produced

by Eq. (1) as follows:

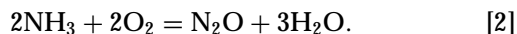


Figure 4 shows infrared spectra of gases produced by oxidation of CH<sub>3</sub>CN on SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Pd (0.2 wt%) at various temperatures for 20 min, where the concentrations of CH<sub>3</sub>CN and air are 20 and 300 Torr, respectively. In the range of 140–200°C, no bands except for CH<sub>3</sub>CN were observed, indicating that the oxidation of CH<sub>3</sub>CN did not occur. However, at 240°C, bands due to CO<sub>2</sub> (2361 cm<sup>-1</sup>) and NH<sub>3</sub> (964 and 930 cm<sup>-1</sup>), appeared, indicating that the oxidation reaction occurred according to Eq. [1]. At 300°C, as shown in Fig. 4, most of the CH<sub>3</sub>CN was oxidized and the bands due to N<sub>2</sub>O (2238 and 2211 cm<sup>-1</sup>) and H<sub>2</sub>O (1624 cm<sup>-1</sup>) appeared as a result of the oxidation of NH<sub>3</sub> produced by Eq. [1] according to Eq. [2].

It is well known that Pd is a very active catalyst for a variety of oxidation reactions (17, 18). The oxidation state of Pd in a SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Pd thick film sintered at 700°C for 1 h was examined by XPS of Pd 3d. As shown in Fig. 5, the oxidation states of Pd were 4+, 2+, and 0 with the relative ratio of 56:29:15. The major oxidation state of Pd was 2+ with a relative content of 56% and the existence of

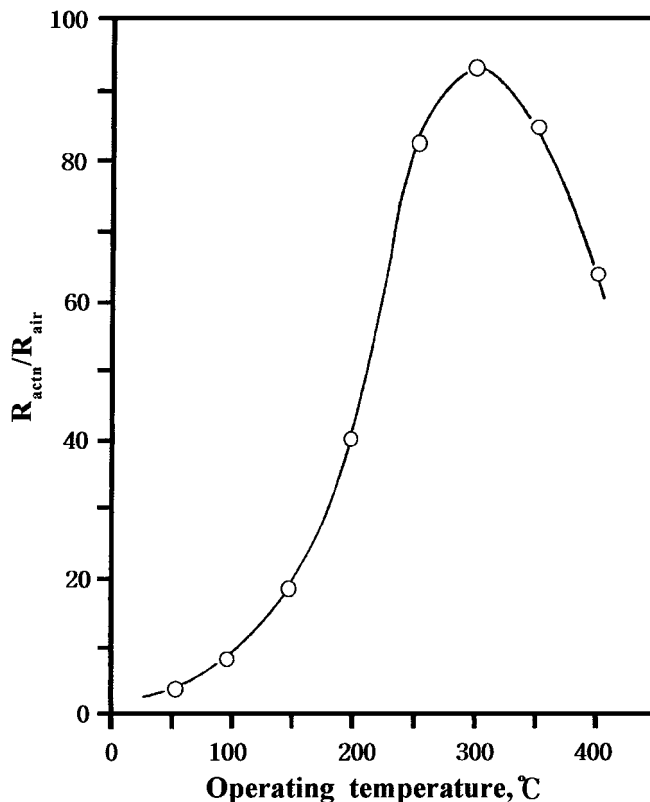
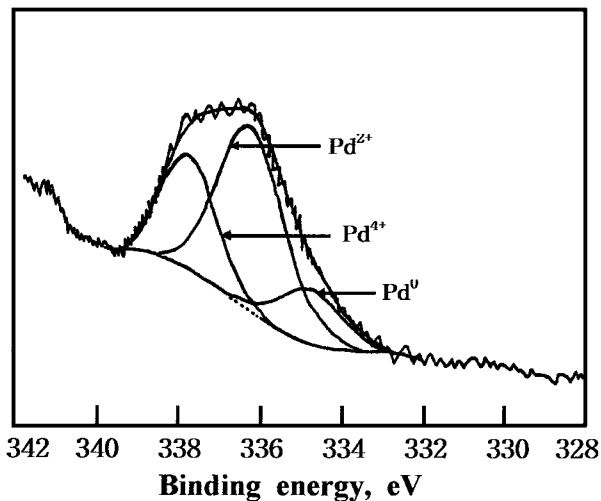


FIG. 6. Sensitivity of the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Pd (0.2 wt%) thick film device to CH<sub>3</sub>CN at various operating temperatures.

metallic Pd was confirmed as shown in Fig. 5. Yamazoe and co-workers also proved the presence of metallic Pd particles in their SnO<sub>2</sub> sintered at 600°C by X-ray diffraction analyses (19). PdCl<sub>2</sub> seems to decompose into metallic Pd, which is mainly oxidized to PdO in air below 650°C. At higher temperature, PdO seems to undergo further oxidation to PdO<sub>2</sub>. In the case of SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Pd it seems likely that metallic Pd plays a significant role as a co-catalyst for the oxidation of CH<sub>3</sub>CN.

The addition of small amounts of additives is known to provide better sensitivity (1, 6, 20). Al<sub>2</sub>O<sub>3</sub> was added to improve the stability of the sensor and the adhesion between the sensor and alumina substrate. The addition of Al<sub>2</sub>O<sub>3</sub> (10 wt%) increased the sensitivity to CH<sub>3</sub>CN. We examined the dependence of the Pd level (0–5.0 wt%) on the sensitivity of the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Pd sensor when the concentration of CH<sub>3</sub>CN was 170 ppm. The devices gave the highest sensitivity at 0.2 wt% Pd, and the optimum operating temperature was 300°C as shown in Fig. 6.

Figure 7 shows IR spectra of oxidation products of CH<sub>3</sub>CN on SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub> and SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> at 300°C for 0.5 h. On SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>, the bands (3723, 3635, 2361, and 667 cm<sup>-1</sup>) due to CO<sub>2</sub> and the bands (3414, 3334, 964, and 930 cm<sup>-1</sup>) due to NH<sub>3</sub> were observed similarly to the case of SnO<sub>2</sub> in Fig. 3. However, on a



Peak	Centre (eV)	FWHM (eV)	Height (%)	Area (%)
Pd <sup>4+</sup>	337.7	1.56	55	29
Pd <sup>2+</sup>	336.2	1.92	87	56
Pd <sup>0</sup>	334.8	1.70	26	15

FIG. 5. Pd 3d XPS of SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Pd (0.2 wt%) sintered at 700°C.

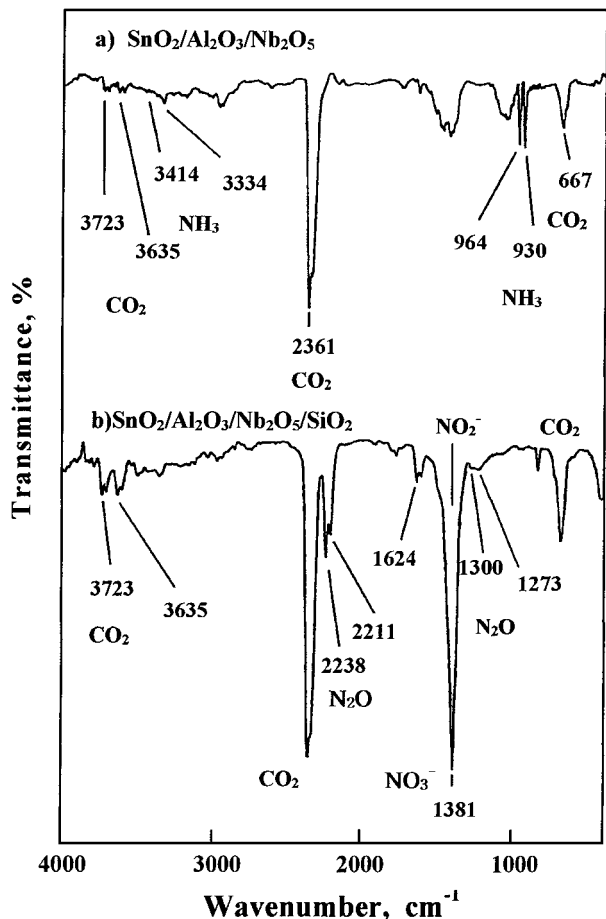
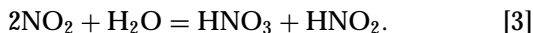


FIG. 7. Infrared spectra after oxidation reaction of CH<sub>3</sub>CN on (a) SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub> and (b) SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> at 300°C for 0.5 h.

SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film, N<sub>2</sub>O bands instead of NH<sub>3</sub> bands appeared at 2238, 2211, and 1300 cm<sup>-1</sup> (16). Also, the bands due to the formation of nitrate or nitrite ions were observed at 1381 and 1358 cm<sup>-1</sup> (16). N<sub>2</sub>O also seems to form by the oxidation of NH<sub>3</sub> produced by Eq. [1] according to Eq. [2]. Also, for the IR absorption bands due to nitrate and nitrite groups, the following reaction is assumed to occur (21):



Oxidation of CH<sub>3</sub>CN on a SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub> thick film produced NH<sub>3</sub>, as shown in Fig. 7. NH<sub>3</sub> oxidation was carried out in a gas cell to examine the behavior of NH<sub>3</sub> produced on the thick film, where the concentrations of NH<sub>3</sub> and air were 20 and 300 Torr, respectively. The results are illustrated in Fig. 8. After reaction of NH<sub>3</sub> on SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub> at 300°C for 1 h, other products except NH<sub>3</sub> were not detected, while at 350°C the bands of H<sub>2</sub>O (3450 and 1624 cm<sup>-1</sup>) and N<sub>2</sub>O (2238 and 2211 cm<sup>-1</sup>, doublet, and 1300 and 1273 cm<sup>-1</sup>, doublet) appeared. These results indicate that NH<sub>3</sub> is oxidized by Eq. [2] and

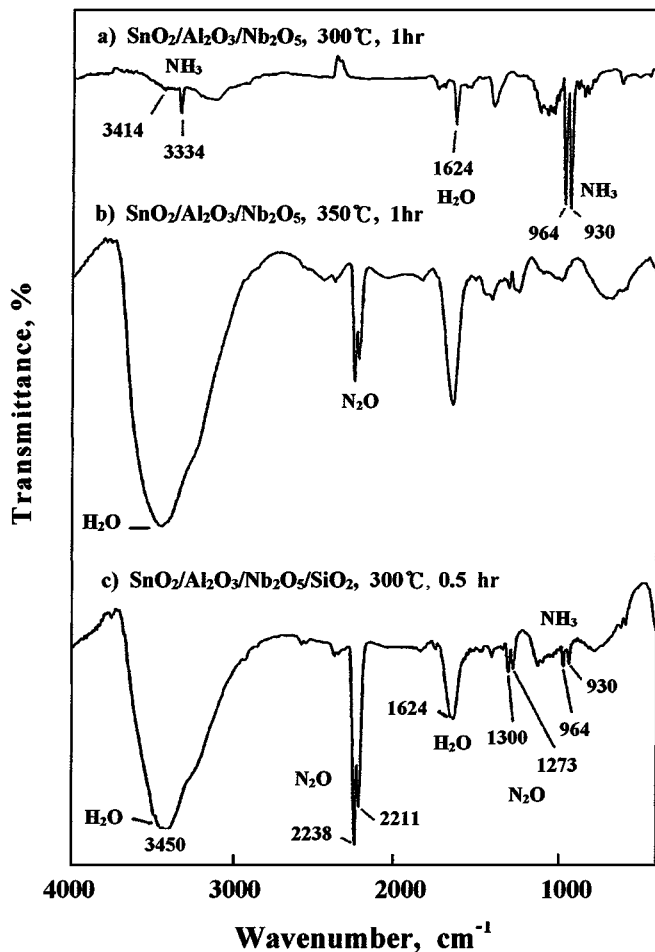


FIG. 8. Infrared spectra after an oxidation reaction of NH<sub>3</sub> on (a, b) SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub> and (c) SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub>.

the reaction occurs to a greater extent at 350°C than at 300°C. On the other hand, oxidation of NH<sub>3</sub> on SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> proceeded very easily, even at 300°C, as shown in Fig. 8c. Considering that the operating temperature of the sensor is 300°C, it is expected that the addition of SiO<sub>2</sub> has a significant effect on the characteristics and sensing selectivity of a SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub> sensor.

Specific surface areas of some samples are listed in Table 2. The surface area of SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> is remarkably large compared to those of the other samples. It

TABLE 2

Specific Surface Areas of Some Samples

Sample	Surface area (m <sup>2</sup> /g)
SnO <sub>2</sub>	5.0
SnO <sub>2</sub> /Al <sub>2</sub> O <sub>3</sub> /Pd	10.5
SnO <sub>2</sub> /Al <sub>2</sub> O <sub>3</sub> /Nb <sub>2</sub> O <sub>5</sub>	22.0
SnO <sub>2</sub> /Al <sub>2</sub> O <sub>3</sub> /Nb <sub>2</sub> O <sub>5</sub> /SiO <sub>2</sub>	84.6

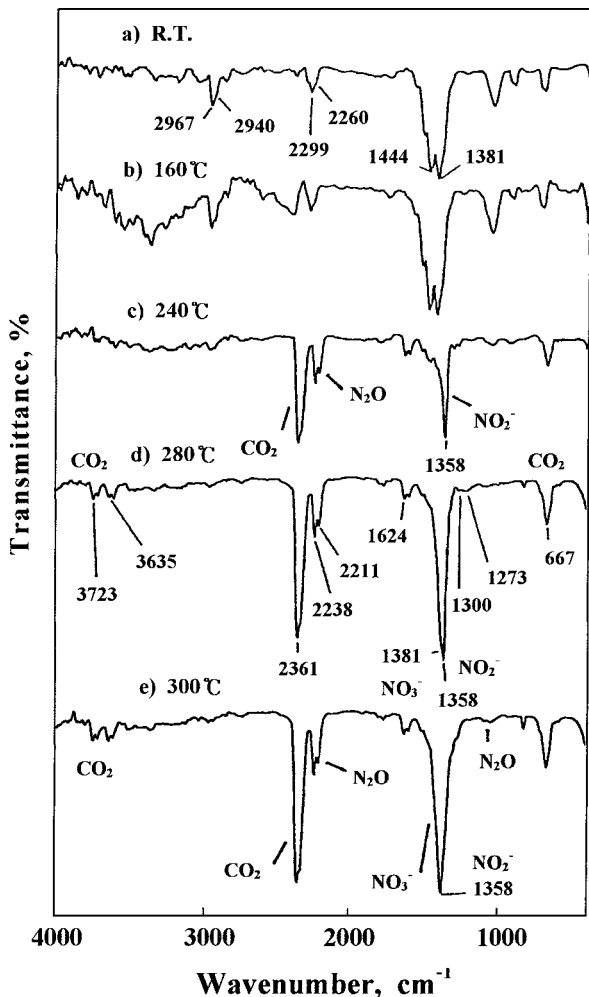


FIG. 9. Infrared spectra after an oxidation reaction of CH<sub>3</sub>CN on SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> at various temperatures for 0.5 h.

seems likely that the surface area also influences the sensing characteristics of the sensor.

Figure 9 shows infrared spectra of gases obtained by oxidation of CH<sub>3</sub>CN on SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> at various temperatures for 0.5 h, where the concentrations of CH<sub>3</sub>CN and air are 20 and 300 Torr, respectively. From room temperature to 160°C, no bands except for CH<sub>3</sub>CN were observed, indicating that oxidation of CH<sub>3</sub>CN did not occur. At 240°C, bands due to CO<sub>2</sub> (2361 cm<sup>-1</sup>), N<sub>2</sub>O (2238 and 2211 cm<sup>-1</sup>), HNO<sub>3</sub> (1381 cm<sup>-1</sup>), and HNO<sub>2</sub> (1358 cm<sup>-1</sup>) appeared and their intensities increased with reaction temperature as shown in Fig. 9. It is known that NH<sub>3</sub>, CO<sub>2</sub>, and H<sub>2</sub>O increase the electric conductivity of a sensor, while N<sub>2</sub>O, HNO<sub>3</sub>, and HNO<sub>2</sub> decrease the conductivity (13). In view of Figs. 7 and 9, the products formed by oxidation of CH<sub>3</sub>CN at 300°C on the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub> thick film were mainly CO<sub>2</sub>, H<sub>2</sub>O, and NH<sub>3</sub>, while on the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film products such as CO<sub>2</sub>, H<sub>2</sub>O, N<sub>2</sub>O, HNO<sub>3</sub>, and HNO<sub>2</sub> were observed. Namely, the catalytic activity and

selectivity of the above two thick films for the oxidation of CH<sub>3</sub>CN are very different. These results explain why SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film devices show high selectivity and negative sensitivity to CH<sub>3</sub>CN. It is clear that the SiO<sub>2</sub> component plays a great role in determining the detection limit of the sensor.

We examined the dependence of the Nb<sub>2</sub>O<sub>5</sub> level (0.2–2.0 wt%) on the sensitivity of the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> sensor, when the concentration of CH<sub>3</sub>CN was 17 ppm and the operating temperature was 300°C. The SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> devices showed the negative sensitivity by increasing the resistance to CH<sub>3</sub>CN, while the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub> devices without SiO<sub>2</sub> exhibited the positive sensitivity to CH<sub>3</sub>CN. As shown in Fig. 10, the devices gave the highest sensitivity at 1.0 wt% Nb<sub>2</sub>O<sub>5</sub>, showing the increased resistance 22–35 times higher than that in fresh air.

The sensing characteristics of the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> device are illustrated as a function of CH<sub>3</sub>CN concentration at various operating temperatures in Fig. 11. The sensitivity increased with increasing concentration of CH<sub>3</sub>CN and the optimum operating temperature was 300°C. It seems likely that the formation of large amounts

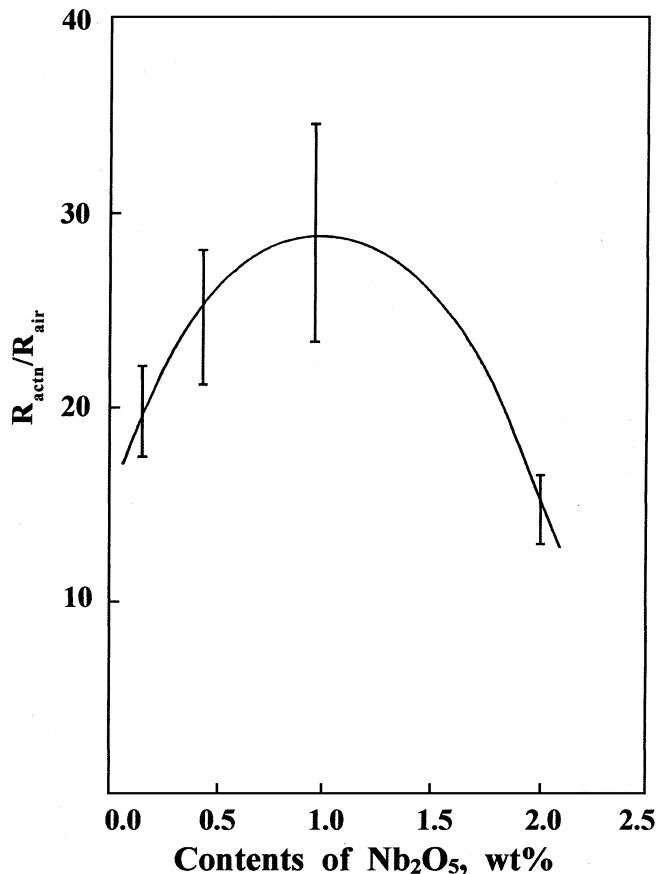


FIG. 10. Sensitivity of the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film device to CH<sub>3</sub>CN as a function of Nb<sub>2</sub>O<sub>5</sub> content at 300°C.

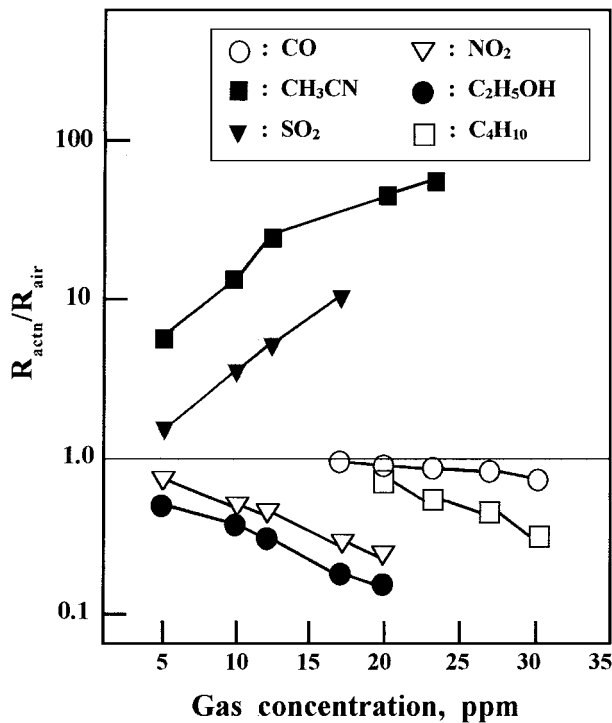


FIG. 11. Sensitivity of the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film device to CH<sub>3</sub>CN at various operating temperatures.

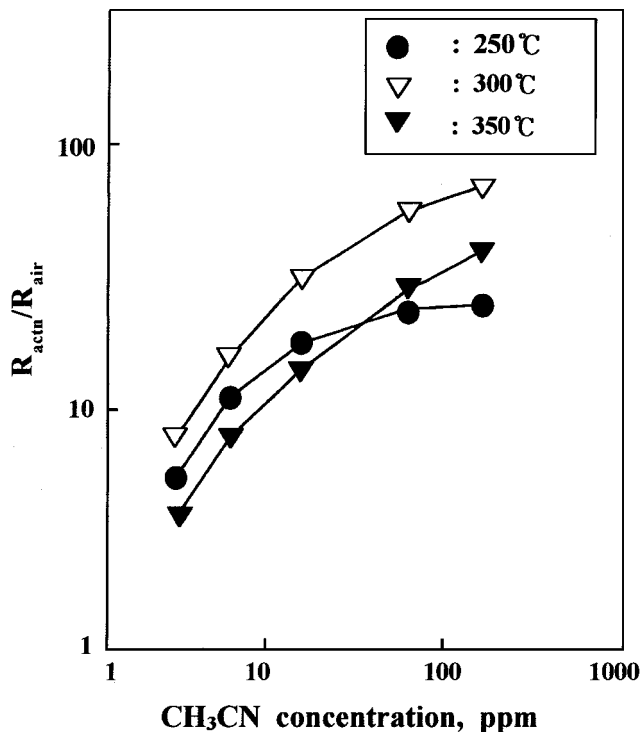


FIG. 12. Resistance characteristics of the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film device to various gases at 300°C.

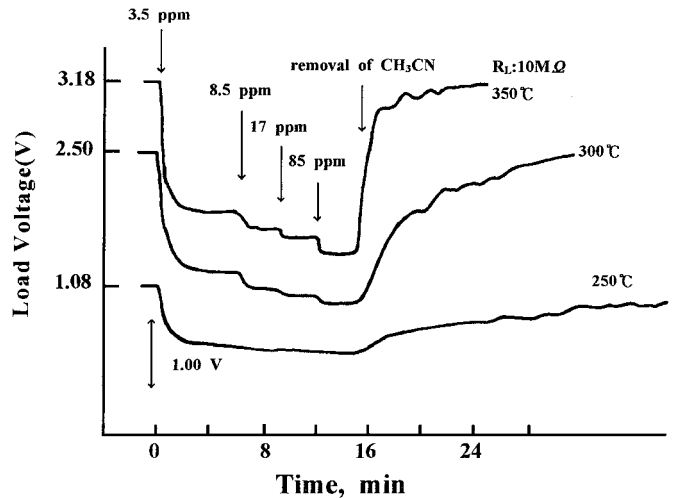


FIG. 13. Transient responses of the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film device to CH<sub>3</sub>CN at different operating temperatures.

of nitrogen compounds such as N<sub>2</sub>O, HNO<sub>3</sub>, and HNO<sub>2</sub>, which decrease the electric conductivity (13), as shown in Fig. 9, is responsible for the decreased sensitivity at 350°C.

Figure 12 shows sensing characteristics of the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> device to various gases at the operating temperature of 300°C. The device exhibited the positive characteristic, resistance decrease, upon exposure to CO, NO<sub>2</sub>, C<sub>4</sub>H<sub>10</sub>, and C<sub>2</sub>H<sub>5</sub>OH, while the device exhibited a negative characteristic upon exposure to CH<sub>3</sub>CN and SO<sub>2</sub>. These results are in good agreement with the fact that, as shown in Fig. 7, SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> produces N<sub>2</sub>O, HNO<sub>3</sub>, and HNO<sub>2</sub>, which decrease the electric conductivity of the sensor (13). Therefore, the gas sensor shows high sensitivity and selectivity to CH<sub>3</sub>CN among various gases without SO<sub>2</sub>. However, since the gas sensor also shows sensitivity to SO<sub>2</sub>, as shown in Fig. 12, it is necessary for us to not use the device under the circumstances containing both CH<sub>3</sub>CN and SO<sub>2</sub>.

Figure 13 shows the transient response characteristics of the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> sensor to CH<sub>3</sub>CN. The sensor was very sensitive to low gas concentration and the gas sensitivity tended to saturate in the range of high concentration (100 ppm). Also, the sensor showed excellent recovery characteristics as the operating temperature increased. These results indicate that the response characteristics and sensitivity depend on the operating temperature. At 300°C, the response and recovery times are 3 s and 10 min, respectively.

## CONCLUSIONS

The SnO<sub>2</sub>-based thick film devices for the detection of CH<sub>3</sub>CN were fabricated by the screen printing and dipping methods. For the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Pd thick film, metallic Pd played a great role as a co-catalyst for the oxidation

of CH<sub>3</sub>CN. Also, the high surface area of SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> influenced the sensing characteristics of the sensor. The oxidation products of CH<sub>3</sub>CN on a SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film were CO<sub>2</sub>, H<sub>2</sub>O, N<sub>2</sub>O, HNO<sub>3</sub>, and HNO<sub>2</sub>. The device exhibited the positive characteristic, resistance decrease, upon exposure to CO, NO<sub>2</sub>, C<sub>4</sub>H<sub>10</sub>, and C<sub>2</sub>H<sub>5</sub>OH, while the device exhibited a negative characteristic upon exposure to CH<sub>3</sub>CN and SO<sub>2</sub>. The oxidizing agents, such as N<sub>2</sub>O, HNO<sub>3</sub>, and HNO<sub>2</sub>, formed by oxidation of CH<sub>3</sub>CN played an important role in determining sensitivity and selectivity to CH<sub>3</sub>CN. The response time and the optimum operating temperature were 3 s and 300°C, respectively.

### REFERENCES

1. McAleer, J. F., Mosely, P. T., Norris, J. O. W., Williams, D. E., and Tofield, B. C., *J. Chem. Soc. Faraday Trans. 1* **84**, 441 (1988).
2. Seiyama, T., Kato, A., Fujiishi, K., and Nagatanui, M., *Anal. Chem.* **34**, 1502 (1962).
3. Lee, D. D., Sohn, B. K., and Ma, D. S., *Sens. Actuators* **12**, 441 (1987).
4. Torvela, H., Romppainen, P., and Loppävuori, S., *Sens. Actuators* **14**, 19 (1988).
5. Egashira, M., Yoshida, M., and Kawasumi, S., *Sens. Actuators* **9**, 147 (1986).
6. Yamazoe, N., Kurokawa, Y., and Seiyama, T., *Sens. Actuators* **4**, 283 (1983).
7. McAleer, J. F., Moseley, P. T., Norris, J. O. W., Williams, D. E., and Tofield, B. C., *J. Chem. Soc. Faraday Trans. 1* **84**, 441 (1988).
8. Torvela, H., Romppainen, P., and Leppävuori, S., *Sens. Actuators B* **4**, 479 (1991).
9. Fryberger, T. B., and Semancik, S., *Sens. Actuators B* **2**, 305 (1990).
10. Klober, J., Ludwig, M., and Schneider, H. A., *Sens. Actuators B* **3**, 69 (1991).
11. Katsuki, A., and Fukui, K., *Sens. Actuators B* **52**, 30 (1998).
12. Nitta, M., and Haradome, M., *J. Electron. Master* **8**, 571 (1979).
13. Park, H. D., Cho, S. G., Sohn, J. R., and Lee, D. D., *J. Korean Sensor Soc.* **2**, 17 (1993).
14. Sohn, J. R., Cho, S. G., Pae, Y. I., and Hayashi, S., *J. Catal.* **159**, 170 (1996).
15. Knoezinger, H., and Krietenbrink, H., *J. Chem. Soc. Faraday Trans. 1* **71**, 2421 (1975).
16. Nakamoto, K., "Infrared and Raman Spectra of Inorganic and Coordination Compounds." Wiley Interscience, New York, 1978.
17. Schlögl, R., Loose, G., Wesemann, M., and Baiker, A., *J. Catal.* **137**, 139 (1992).
18. Ribeiro, F. H., Chow, M., and Dalla Betta, R. A., *J. Catal.* **146**, 537 (1994).
19. Matsushima, S., Teraoka, Y., Miura, N., and Yamazoe, N., *Jpn. J. Appl. Phys.* **27**, 1798 (1988).
20. Wada, K., and Egashira, M., *Sens. Actuators B* **53**, 147 (1998).
21. Foster, D. S., and Lesline, S. E., "Encyclopedia of Industrial Chemical Analysis." Wiley Interscience, New York, 1978.